



# **ECE695A: Reliability Physics of Nano-Transistors**

## **Lecture 4: Structures and Defects in Crystals**

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# Outline of lecture 4

1. Background information
2. Defect-free crystal structures
3. Defects in crystals
4. Conclusions

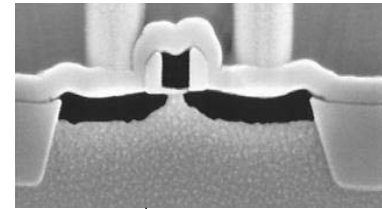
# Transistor and interconnect reliability

## Transistor reliability issues

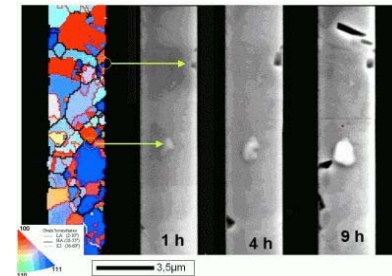
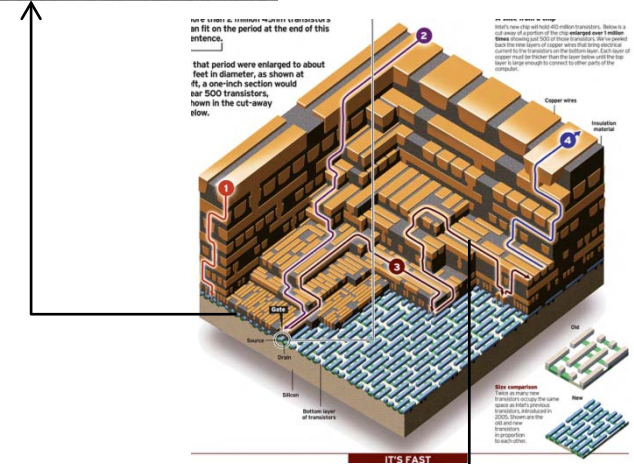
- Gate dielectric breakdown
- Negative bias temperature instability
- Hot carrier degradation
- Radiation induced damage

## Interconnect reliability issues

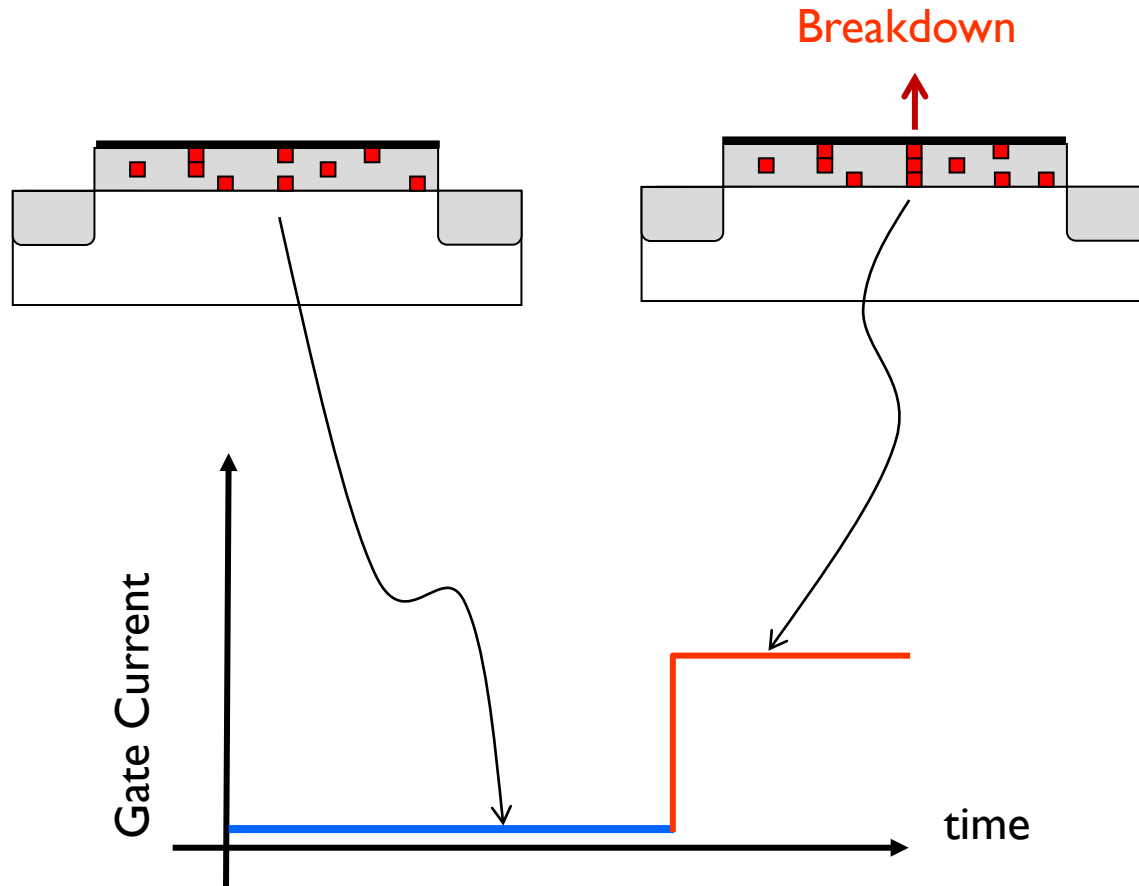
- Electro-migration/Stress-migration.
- Inter-level dielectric breakdown



The Oregonian, 2008

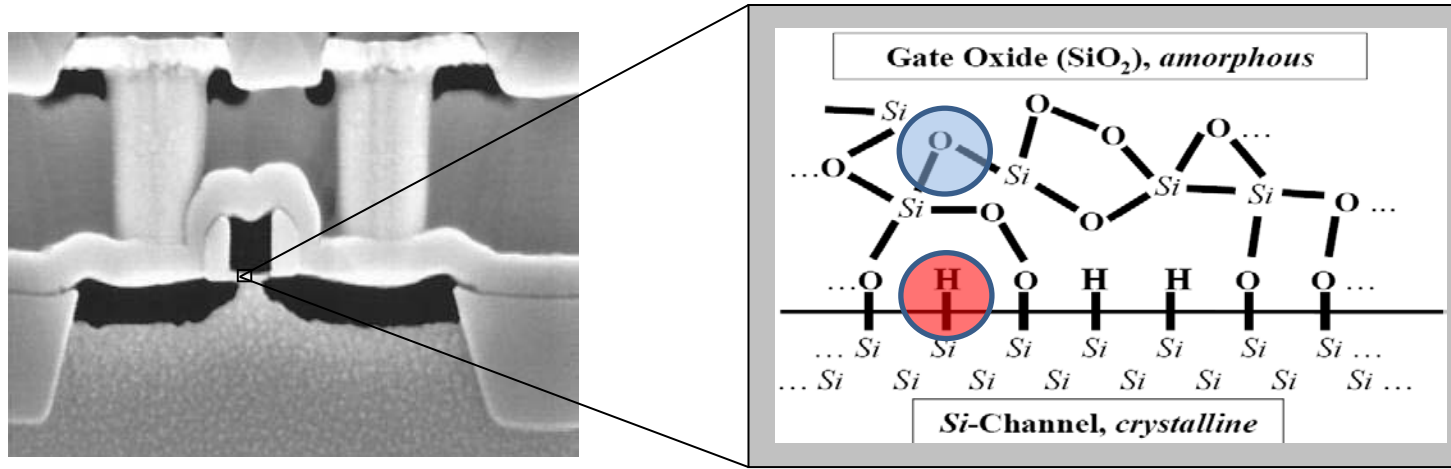


# Defects created during oxide breakdown



What do the red boxes represent physically?

# Broken SiO and SiH bonds



## *Broken Si-H bonds*

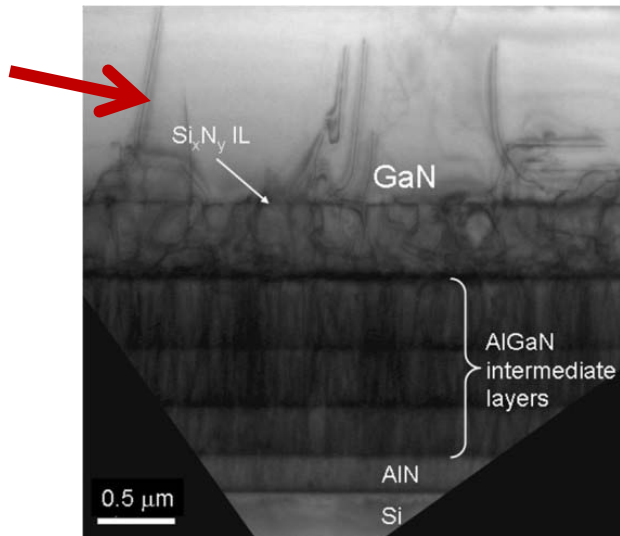
Negative bias temperature instability (NBTI)  
Hot carrier degradation (HCI)

## *Broken Si-O bonds*

Gate dielectric breakdown (TDDB)  
Electrostatic discharge (ESD)  
Radiation induced gate rupture (RBD)

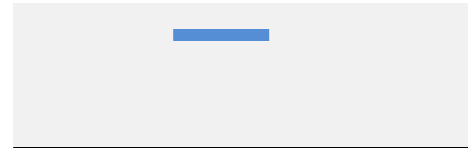
# Defects vs. traps

## Defects

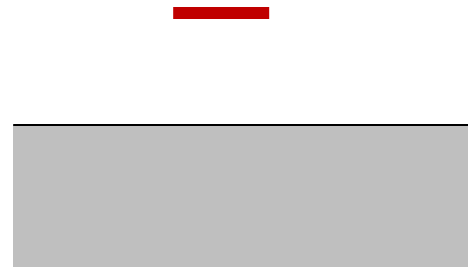


Misplaced atom,  
incomplete bonds

Defects found in images may not be electrically relevant,  
e.g. InGaN/GaN blue Light emitting diodes

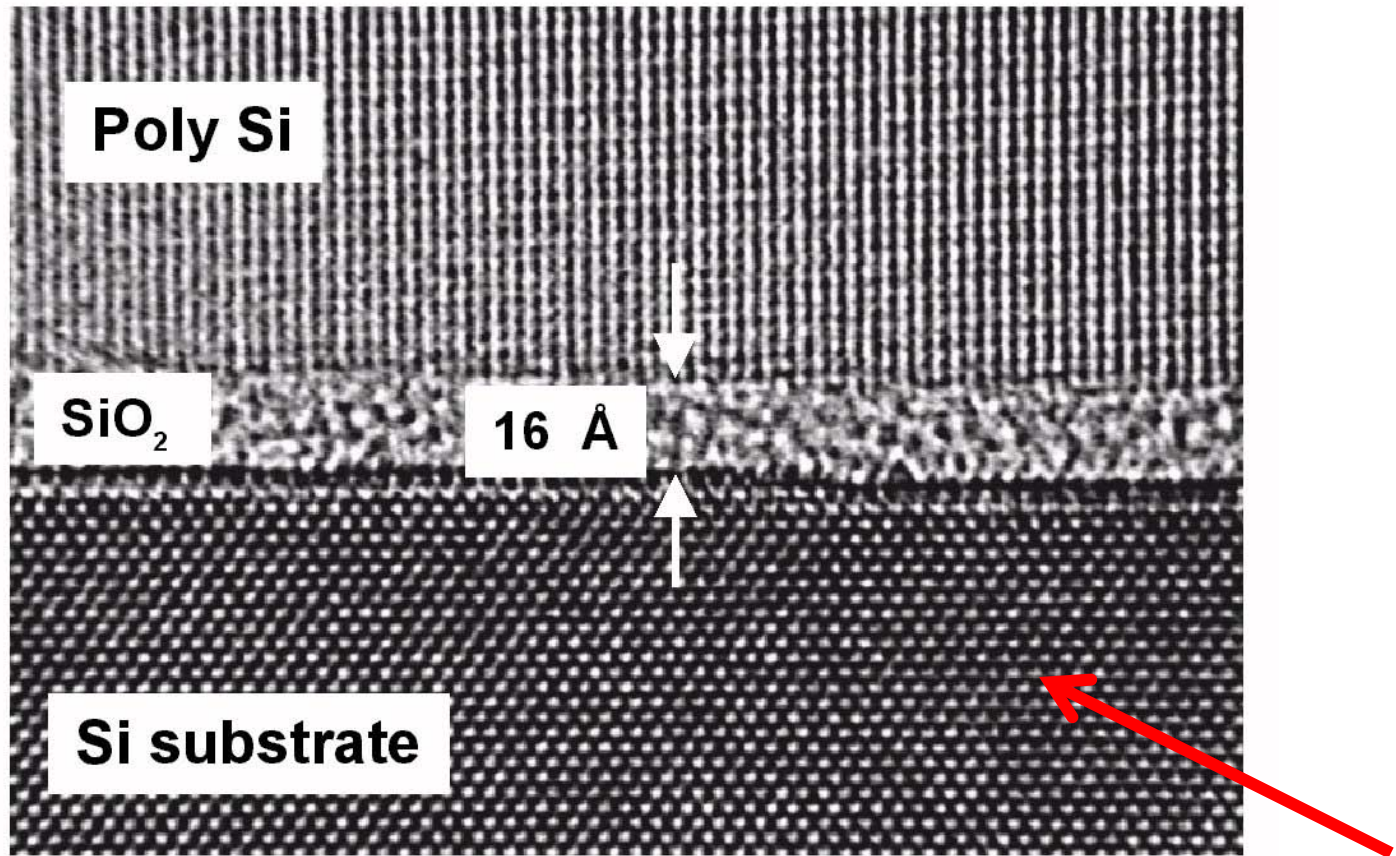


Not a Trap



Trap

# Will begin by defects in crystals

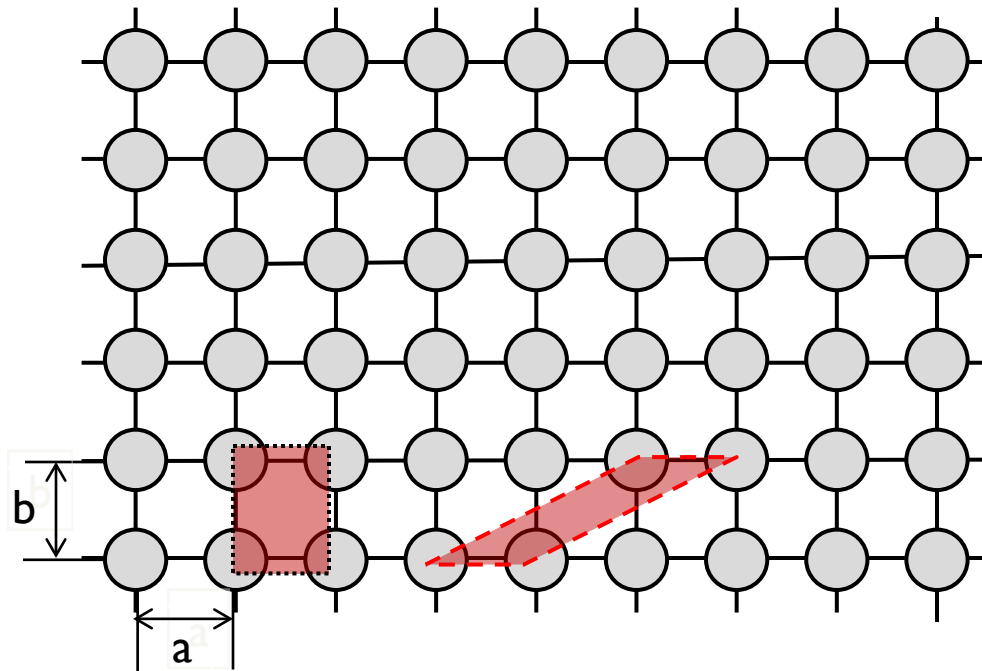




# Outline

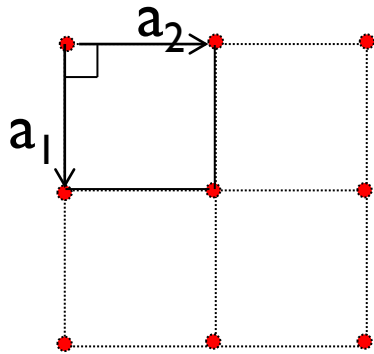
1. Background information
2. Defect-free **crystal** structures
3. Defects in crystals
4. Conclusions

# Unit cell of a periodic lattice

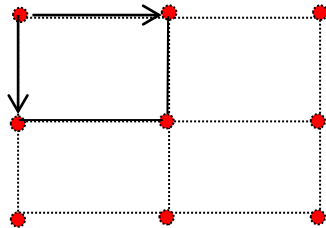


A crystal is represented by unit cells and basis vectors

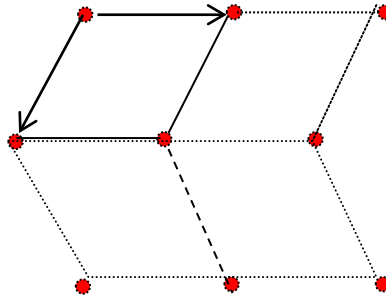
# Periodic lattice in 2D (5-types)



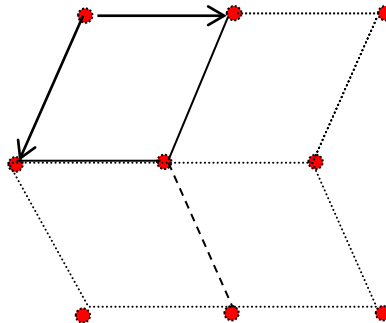
$$a_1 = a_2, \phi = 90$$



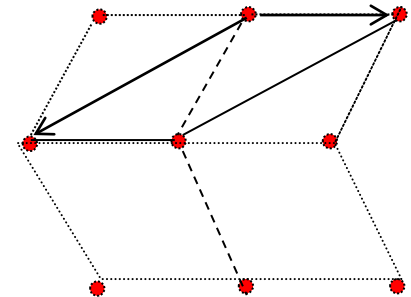
$$a_1 < a_2, \phi = 90$$



$$a_1 = a_2, \phi > 90$$



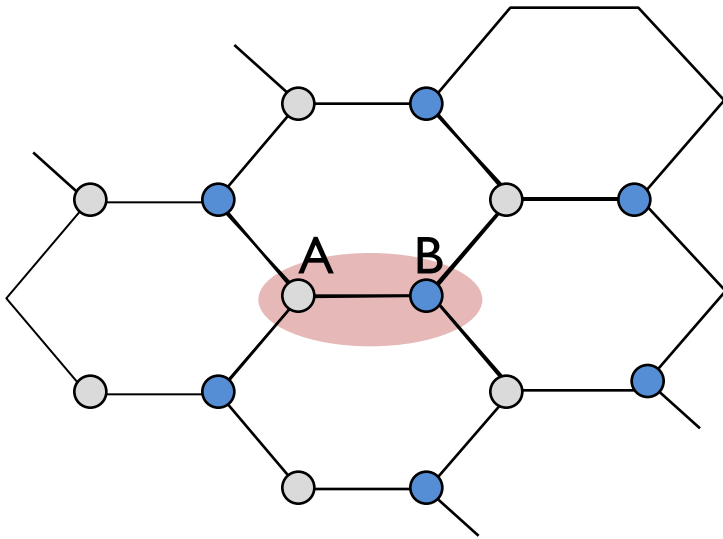
$$a_1 > a_2, \phi > 90$$



General

Many systems have 2D lattice (e.g., graphene, Wigner crystals, ...)

# Not a Bravais lattice ...



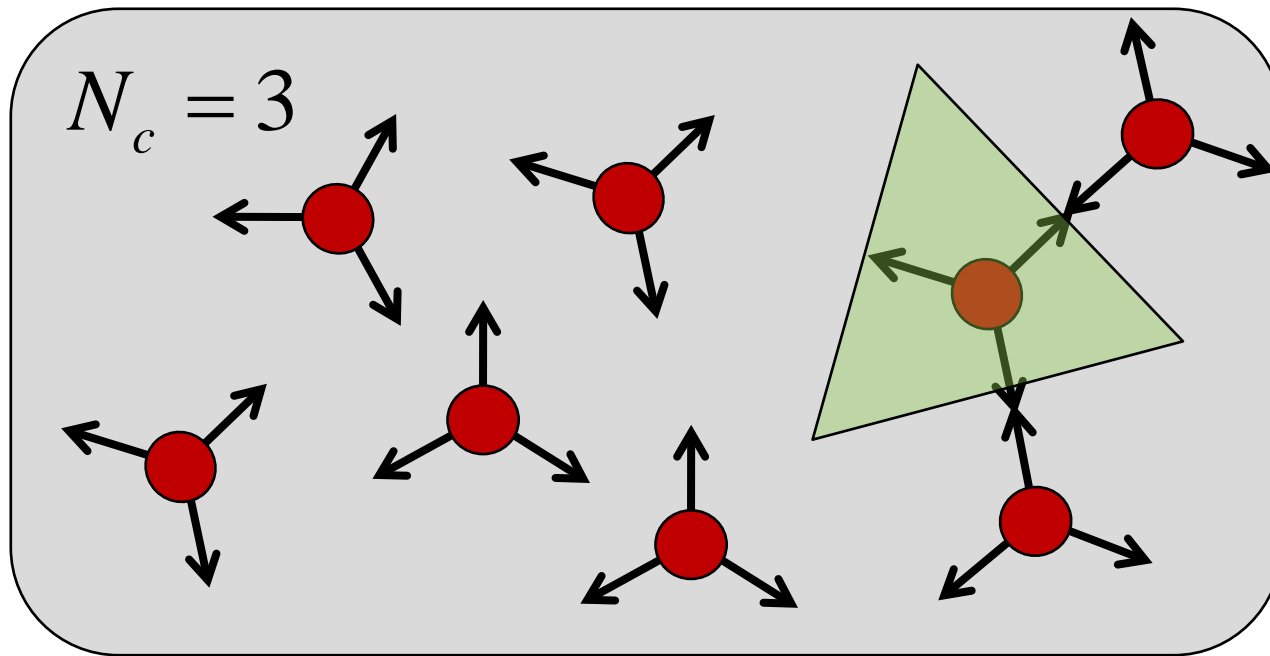
This is graphene sheet which can be obtained from graphite by adhesive tape stamping

*Ref. Novoselov, Geim, et al. Nature, 438, 197, 2005.*

A and B do not have identical environment

Can be converted to Bravais lattice by creating a new basis

# How to crystal arise: Coordination and bonding



# Topology of points and Euler formula

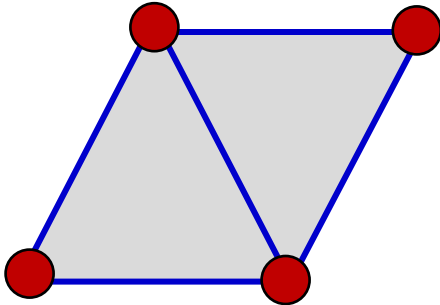
Euler relationship in 2D

$$\textcolor{red}{V} - \textcolor{blue}{E} + N = 1$$

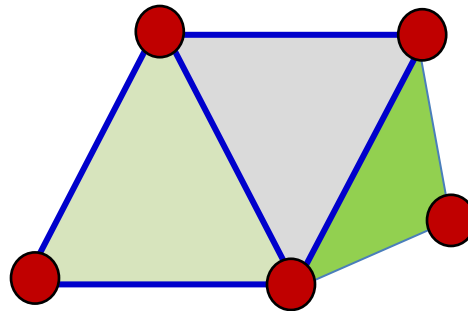
vertices      edges      cell number

For large systems ....

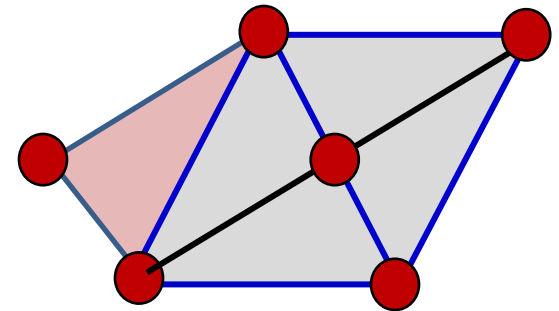
$$\textcolor{red}{V} - \textcolor{blue}{E} + N \approx 0$$



$$\left[ \begin{array}{l} \textcolor{red}{V} = 4 \\ \textcolor{blue}{E} = 5 \\ N = 2 \end{array} \right] \Rightarrow 1$$

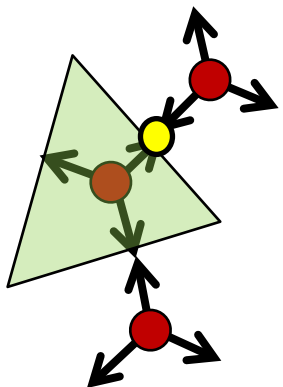


$$\left[ \begin{array}{l} \textcolor{red}{V} = 5 \\ \textcolor{blue}{E} = 7 \\ N = 3 \end{array} \right] \Rightarrow 1$$



$$\left[ \begin{array}{l} \textcolor{red}{V} = 6 \\ \textcolor{blue}{E} = 10 \\ N = 5 \end{array} \right] \Rightarrow 1$$

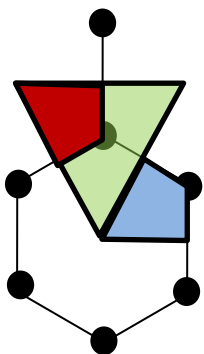
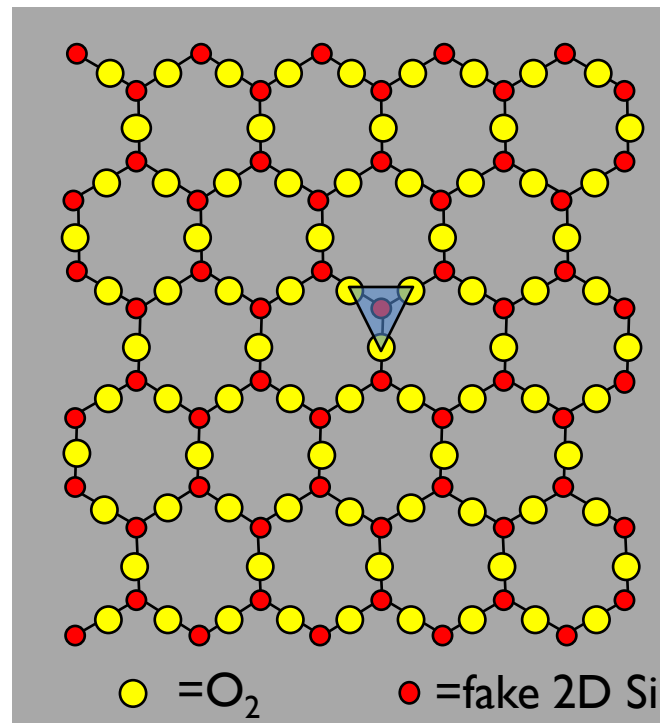
# Euler anticipates 'graphene' lattice



$$\left. \begin{array}{l} V = 1 \\ E = \frac{3}{2} \end{array} \right\} 2E = 3V = N_p N$$

$$V - E + N = 1$$

3 bonds/atoms to  
honeycomb lattice



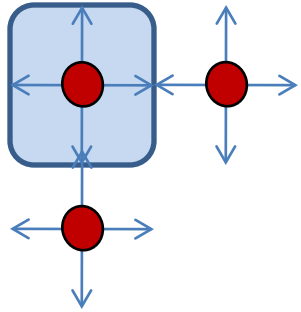
$$\frac{N_p N}{3} - \frac{N_p N}{2} + N \sim 0$$

$$N_p \cong 6 \longleftarrow \text{edges/cell}$$

$$6N = 3V \Rightarrow N = \frac{1}{2}$$

1/2 of a cell; therefore each cell must have **6-sides!**

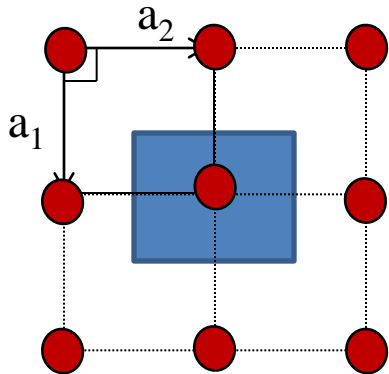
# Exercise: what type of lattice with $N_c=4$ ?



$$\left. \begin{array}{l} V = 1 \\ E = \frac{4}{2} \end{array} \right\} 2E = 4V = N_p N$$

$$V - E + N = 1$$

$$\frac{N_p N}{4} - \frac{N_p N}{2} + N \sim 0$$



$$\Rightarrow N_p \cong 4 \quad \text{Final lattice must have 4 edges/cell}$$

$$4N = 4V \Rightarrow N = 1$$

The volume of each unit must equal the volume of unit lattice



# With Euler relationship, you can.....

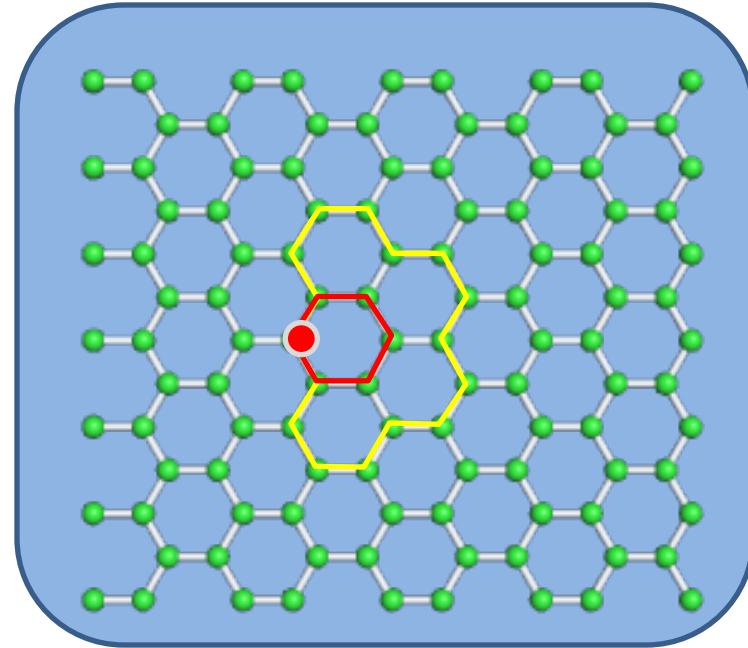
A 6-bond atom leads to triangular lattice

Determine the size of the primitive ring

Show that a five ring lattice is impossible

Calculate Number of rings sharing an atom

Show that odd-number rings are impossible



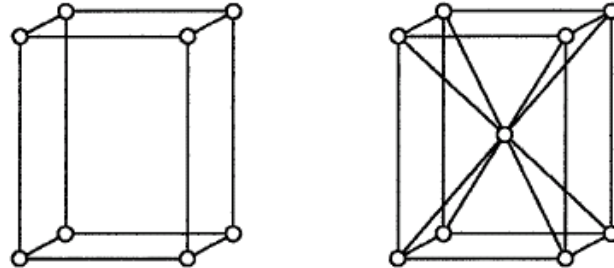
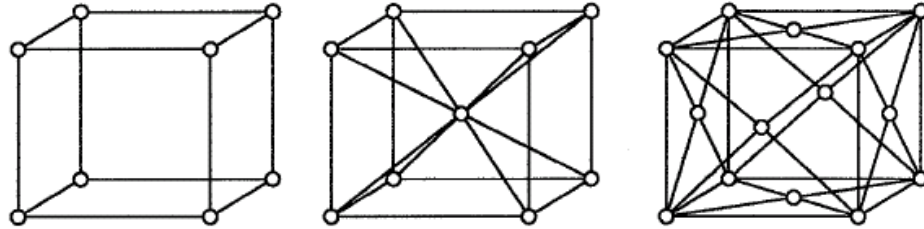
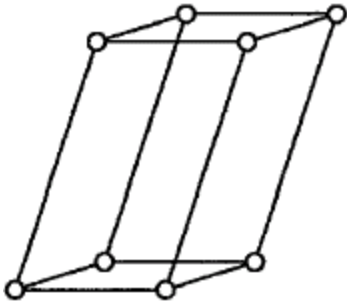
## References.

X.Yuan and A. Cormack, *Computational Material Science*, **24**, p. 343, 2002.

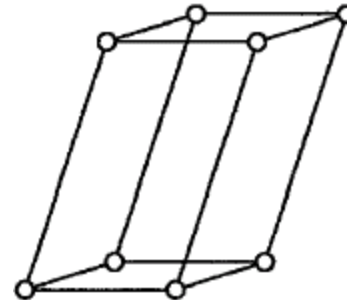
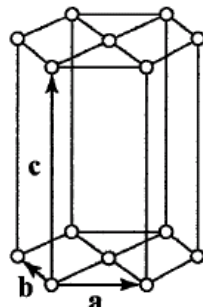
S.V.King *Nature* **213** (1967), p. 1112. <http://rings-code.sourceforge.net/>

# 3D-Bravais lattices

Triclinic

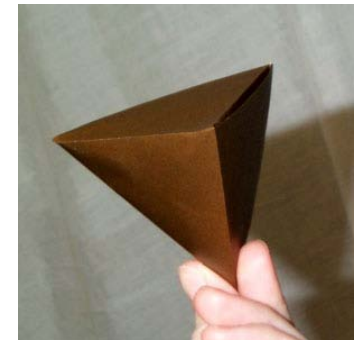
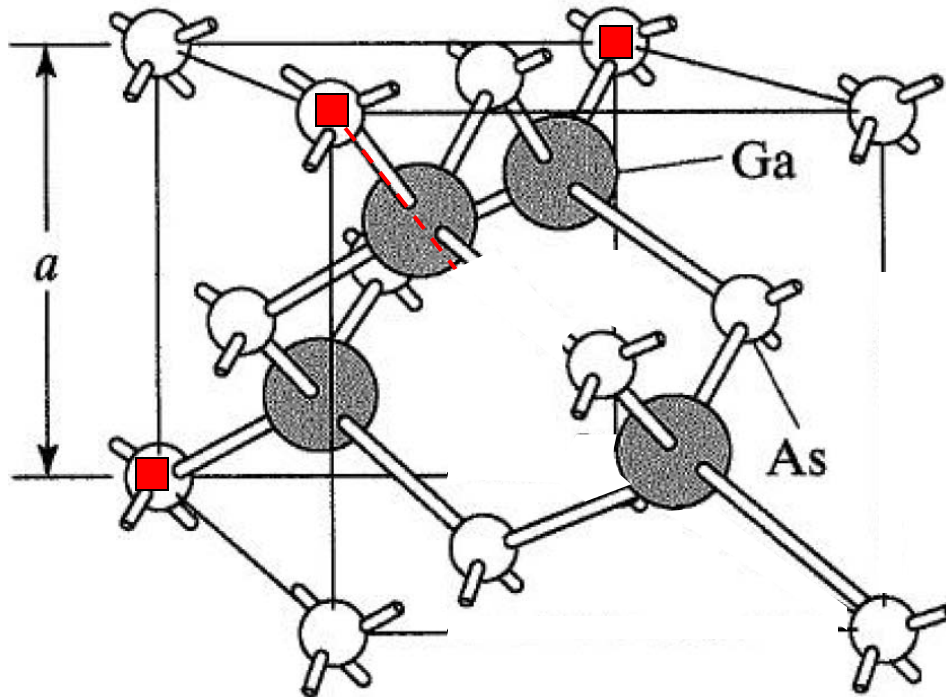


Why  
not ?



And others .....

# Zinc-Blende lattice for GaAs



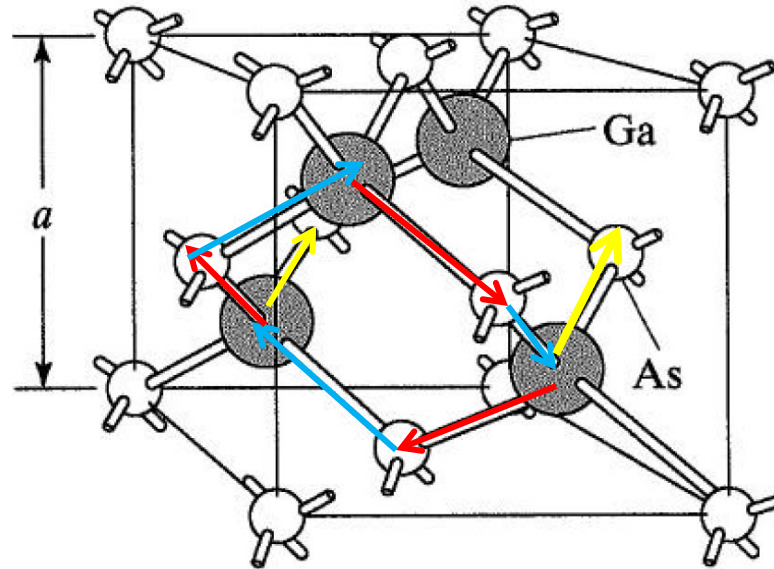
$$\text{Atoms/cell} = (1/8) \times 8 + (1/2) \times 6 + 4 = 8$$

FCC Lattice with a basis

Not a primitive cell

Tetrahedral structure

# Homework: ring statistics



Show that Si has

*6-atoms in the primitive (smallest) ring*

*12 rings through each atoms ( 4 ways out, 3 ways in)*

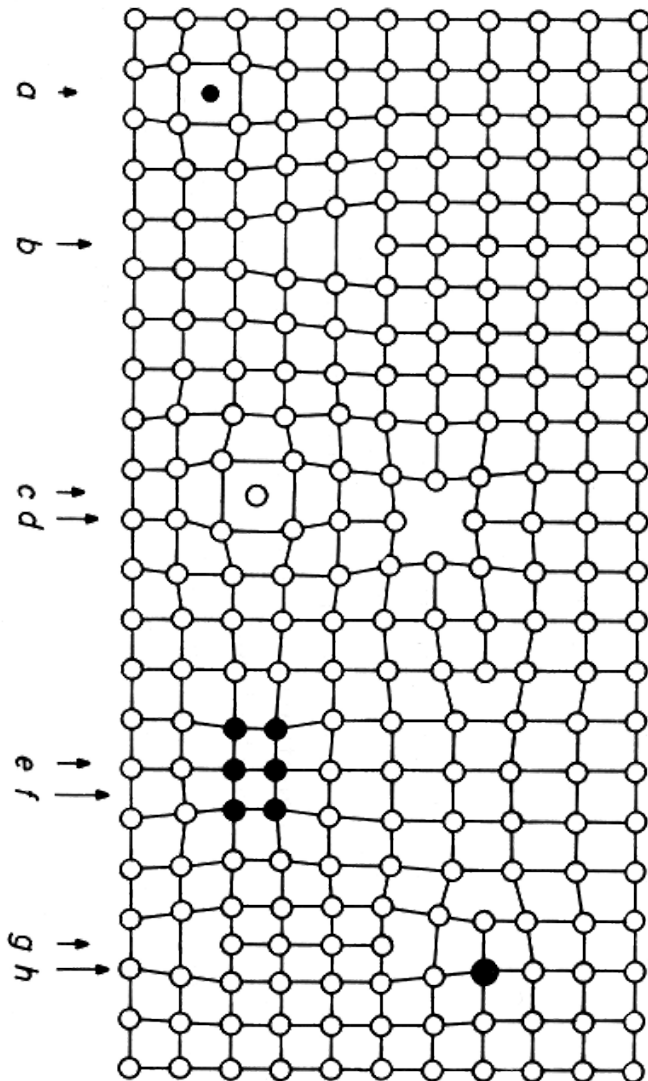
*All rings are even.*

# Outline

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# Types of crystal defects: point & bulk

Now that we know geometry of perfect lattice ...



**a) Interstitial atom**

b) Edge dislocation

**c) Self interstitial atom**

**d) Vacancy**

e) Precipitate of impurity atoms

f) vacancy type dislocation loop

g) Interstitial type dislocation loop

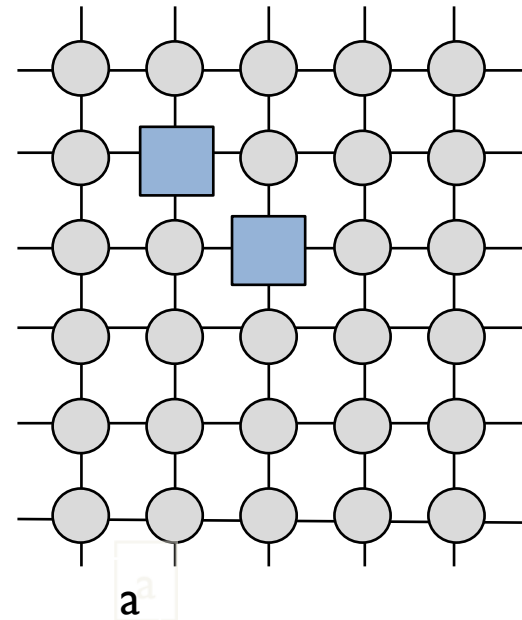
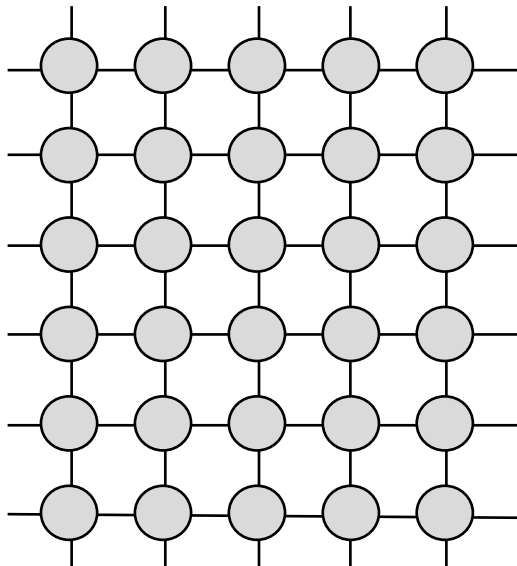
**h) Substitutional impurity atom**

Defects are named formally by Kroger-Vink notation

# Concentration of point defects

Energy of the system:  $F = E - TS$

Vacancy is created if:  $\Delta F = (\Delta E - T \cdot \Delta S) < 0$



$$\frac{\Delta S}{k_B} = -\ln \frac{N!}{N!0!} + \ln \frac{N!}{(N-V)!V!}$$

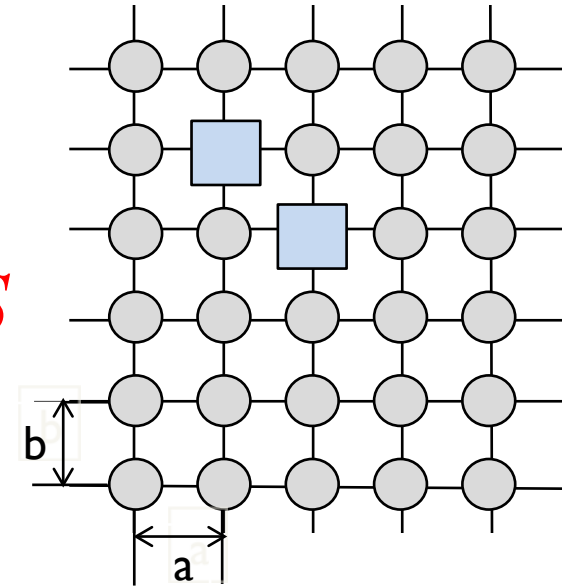
# Concentration of point defects

$$\frac{\Delta S}{k_B} \approx N \ln N - (N - V) \ln(N - V) - V \ln V$$

$$\Delta E \approx E_{after} - E_{before} = E_V V - 0$$

$$\Delta F = F_{after} - F_{before} = +VE_V - k_B T \Delta S$$

Minimize F to for equilibrium  $V$   
(definition of chemical potential) ....



$$V \sim N \times e^{-\frac{E_V}{k_B T}}$$

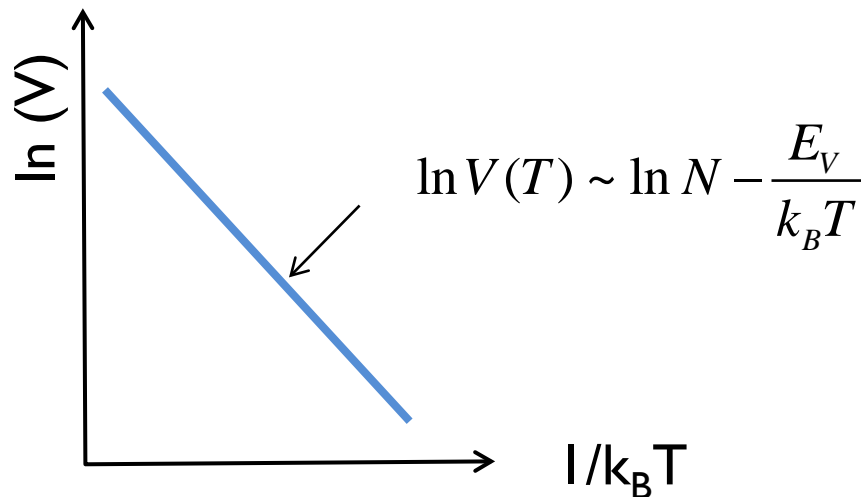


# Example: equilibrium defect density

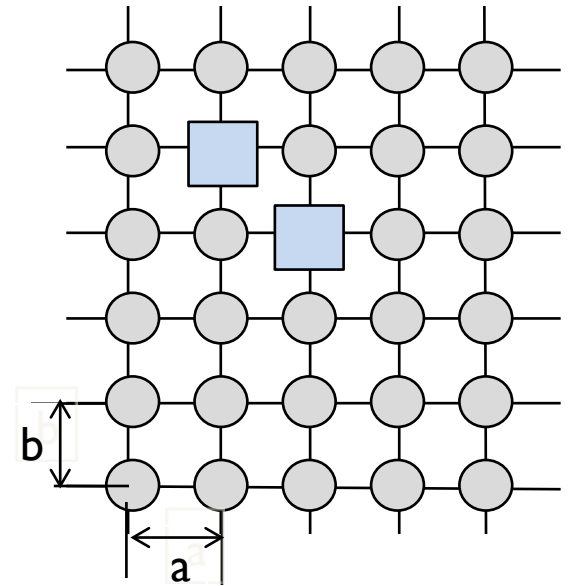
Assume:  $E_V = 1 \text{ eV}$ ,  $T = 1000 \text{ C}$ , find  $V$

Answer: 1 part in  $10^5$  at 1000 C.  
In silicon, the number is  $10^{17} \text{ cm}^{-3}$ !

Activation energy can be obtained from slope of temperature dependent data.



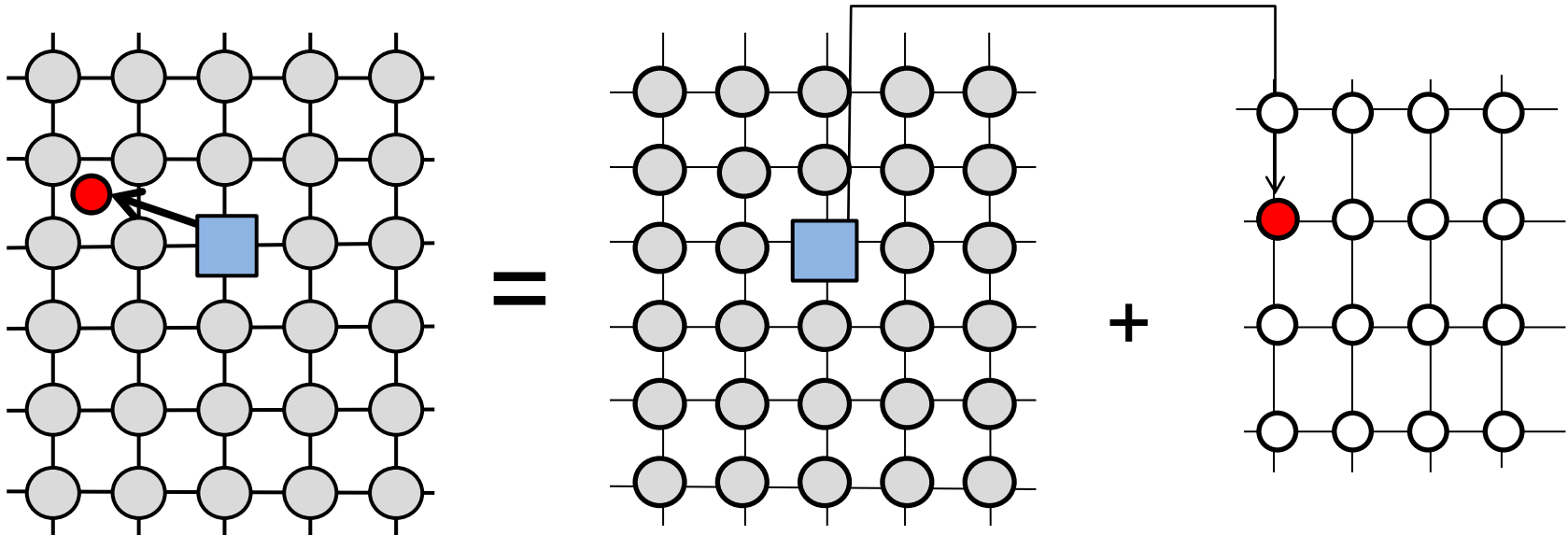
$$V \sim N \times e^{-\frac{E_V}{k_B T}}$$



# Homework: Interstitials

Show that the interstitial concentration is

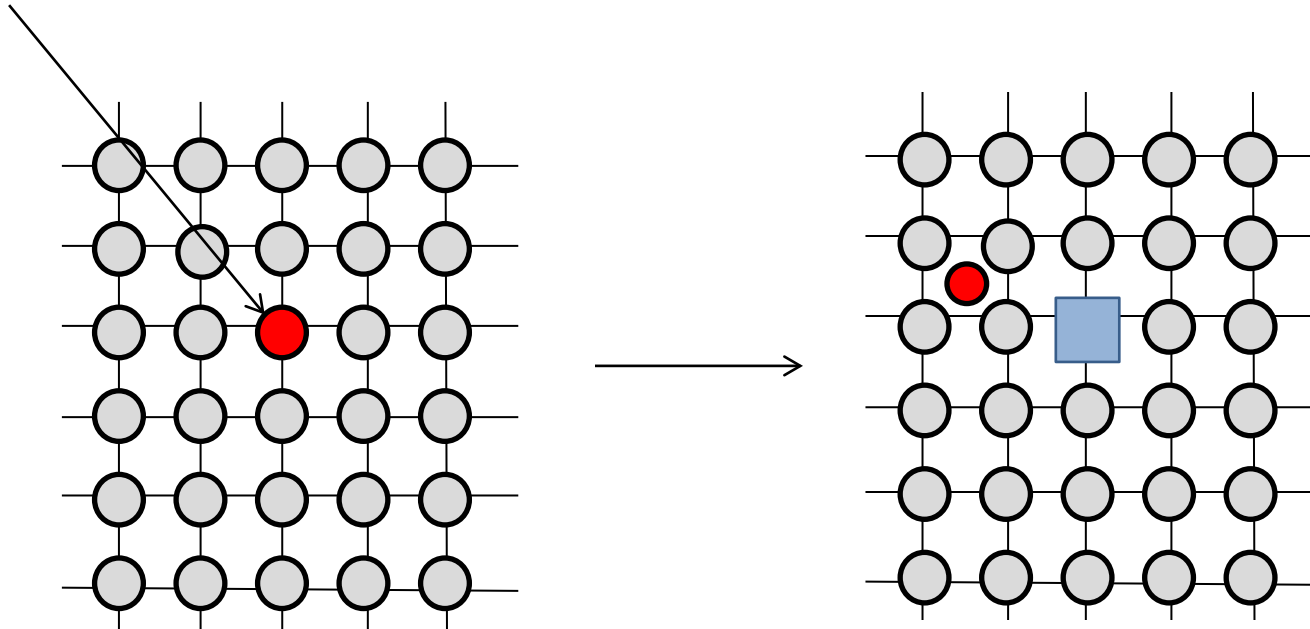
$$I \sim N \times e^{-\frac{(E_V + E_I)}{2k_B T}} \quad E_I \gg E_V$$



Calculate entropy change as a product of two configurations

# Dynamics vs. thermodynamics

Radiation induced generation of bulk defects ...

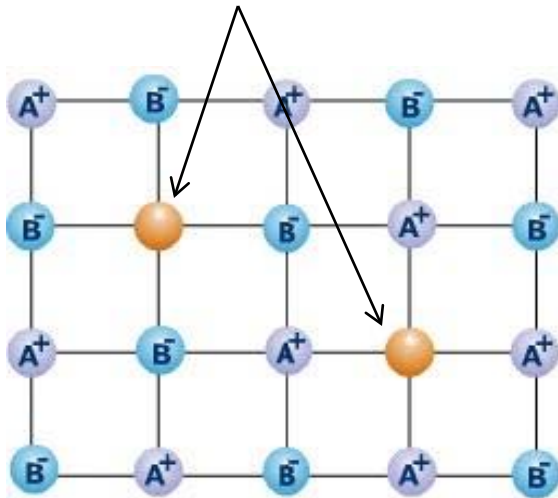


Amorphization by radiation ....

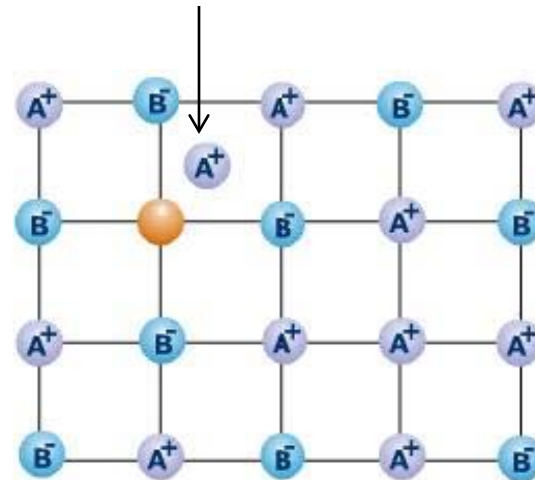
$$I \neq N \times e^{-\frac{E_I}{2k_B T}}$$

# Point defects in ionic crystals

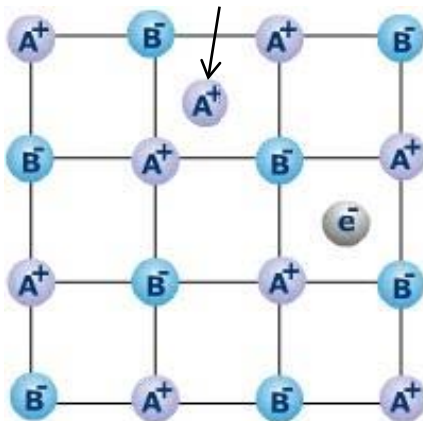
Schottky defect



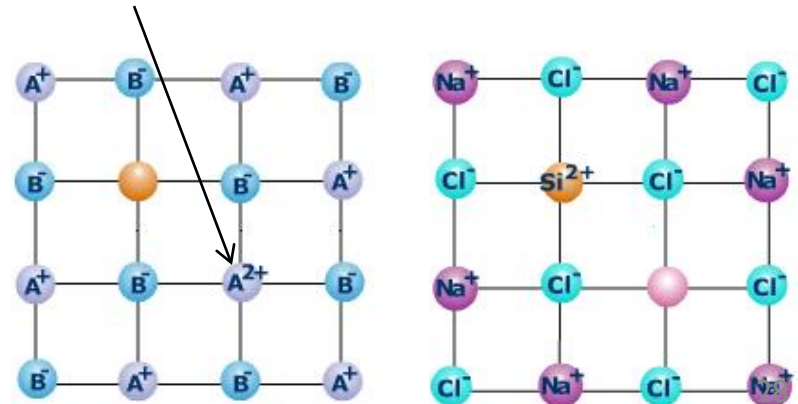
Frenkel defect



Excess metal

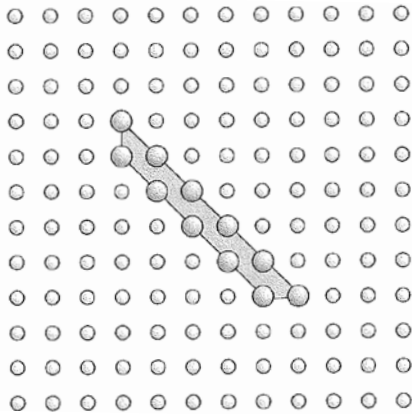


Impurity defect in ionic solids

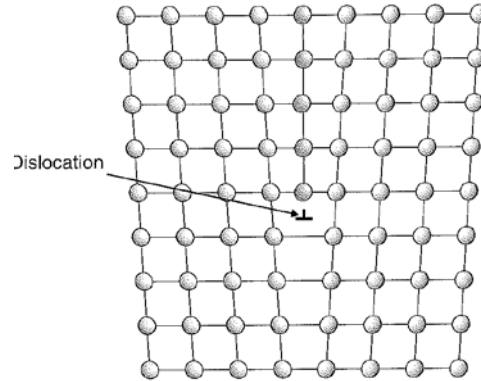


# Hierarchical defects in the crystals

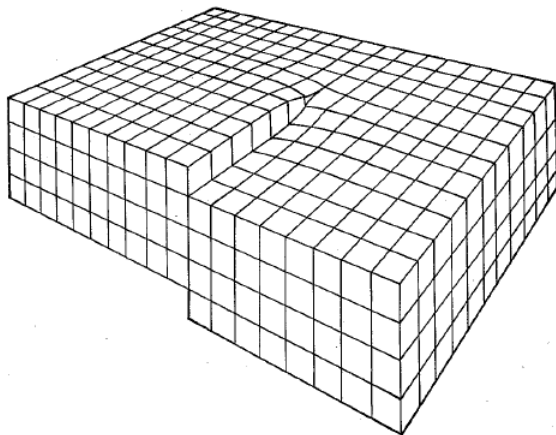
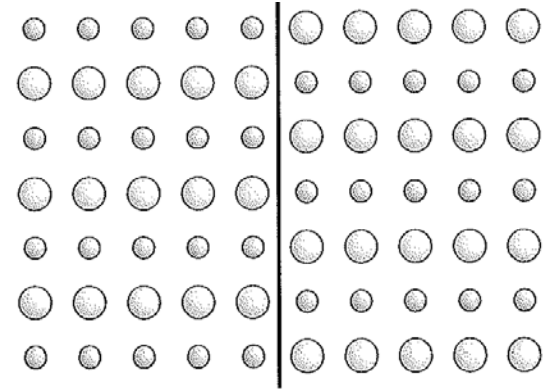
Volume defect



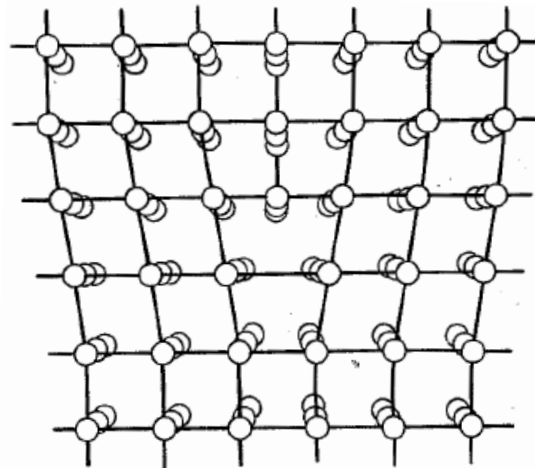
Linear defect



Planar defect



Screw dislocation



Edge dislocation

Defects in Solids,  
Wiley, 2000.

# Conclusions

- ❑ Reliability physics deals with pre-existing defects due to processing and newly created defect due to device operation.
- ❑ Textbooks on device theory assumes perfect crystal and then the defects sneak in through mobility models and phonon lifetime.
- ❑ Standard thermodynamic models predict the creation of defects due to process details. There are hierarchy of these defects.
- ❑ Stress and radiation effects generates new defects that must be obtained from kinetic consideration, not thermodynamics.

# References

- David E. Richeson, Euler's Gem: The Polyhedron Formula and the Birth of Topology, Princeton University Press,
- Frank Neuman, Euler's Gem and The birth of topology, 2010.  
[http://www.tilings.org.uk/T3M2\\_Euler.pdf](http://www.tilings.org.uk/T3M2_Euler.pdf)
- R. Tilley, Defects in Solids, ISBN: 978-0-470-07794-8, Wiley, 2000
- C. Kittel, Introduction to Solid State Physics, 8<sup>th</sup> Edition., ISBN 978-0-471-41526-8, 2004.
- Formation energy of vacancy in silicon determined by a new quenching method . N. Fukata<sup>a</sup>, A. Kasuya<sup>b</sup> and M. Suezawa<sup>a</sup>.
- Defects in GaN  
<http://www.imec.be/ScientificReport/SR2008/HTML/I225014.html>
- Paul Shewmon Diffusion in solids, ISBN-13: 978-0873391054